

ADVANCED FUNCTIONAL MATERIALS

Supporting Information

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Tailoring Vanadium Dioxide Film Orientation Using
Nanosheets: a Combined Microscopy, Diffraction, Transport,
and Soft X-Ray in Transmission Study

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Title**Tailoring Vanadium Dioxide Film Orientation using Nanosheets: A Combined Microscopy, Diffraction, Transport and Soft X-ray in Transmission Study**

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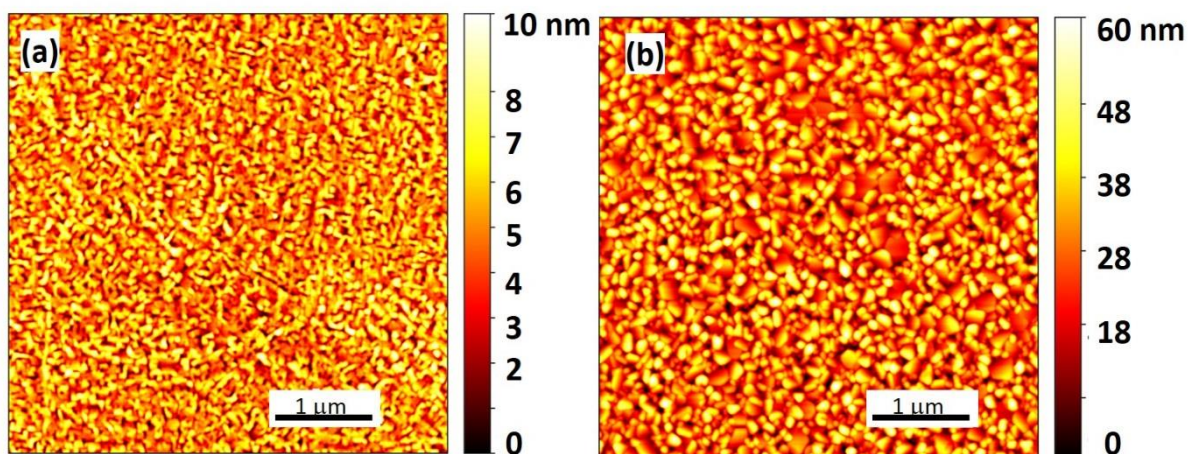


Figure S1. AFM micrographs VO₂ films on nanosheets. (a) VO₂ on TO nanosheets and (b) VO₂ on NWO nanosheets. In each case, the relevant z-scale is shown.

Figure S1 shows the difference in morphology as observed by AFM of VO₂ thin films grown on two types of nanosheets. In particular, there is a difference in domain size, where the growth domains have a roughly 2-3 smaller size when VO₂ is grown on TO compared to NWO. The films grown on NWO have a larger peak-to-peak roughness. This difference presumably is a result of the difference in growth kinetics on either type of nanosheet. Note that the individual nanosheets are non-discernable in these images.